

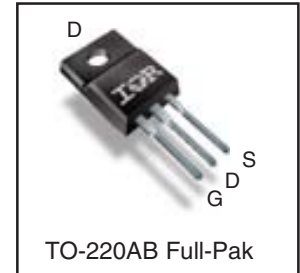
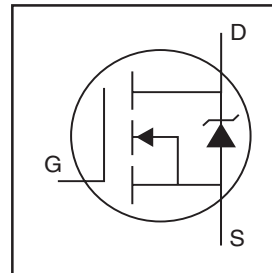
**PDP SWITCH**

**IRFI4229PbF**

**Features**

- Advanced Process Technology
- Key Parameters Optimized for PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $E_{PULSE}$  Rating to Reduce Power Dissipation in PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $Q_G$  for Fast Response
- High Repetitive Peak Current Capability for Reliable Operation
- Short Fall & Rise Times for Fast Switching
- 150°C Operating Junction Temperature for Improved Ruggedness
- Repetitive Avalanche Capability for Robustness and Reliability

Key Parameters		
$V_{DS\ max}$	250	V
$V_{DS\ (Avalanche)\ typ.}$	300	V
$R_{DS(ON)\ typ. @\ 10V}$	38	mΩ
$I_{RP\ max @\ T_C = 100^\circ C}$	32	A
$T_J\ max$	150	°C



G	D	S
Gate	Drain	Source

**Description**

This HEXFET® Power MOSFET is specifically designed for Sustain; Energy Recovery & Pass switch applications in Plasma Display Panels. This MOSFET utilizes the latest processing techniques to achieve low on-resistance per silicon area and low  $E_{PULSE}$  rating. Additional features of this MOSFET are 150°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for PDP driving applications.

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	±30	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	19	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	12	
$I_{DM}$	Pulsed Drain Current ①	72	
$I_{RP} @ T_C = 100^\circ C$	Repetitive Peak Current ⑤	32	
$P_D @ T_C = 25^\circ C$	Power Dissipation	46	W
$P_D @ T_C = 100^\circ C$	Power Dissipation	18	
	Linear Derating Factor	0.37	W/°C
$T_J$	Operating Junction and Storage Temperature Range	-40 to + 150	°C
$T_{STG}$			
	Soldering Temperature for 10 seconds	300	
	Mounting Torque, 6-32 or M3 Screw	10lb·in (1.1N·m)	N

**Thermal Resistance**

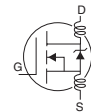
	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	2.73	°C/W
$R_{\theta JA}$	Junction-to-Ambient ④	—	65	

Notes ① through ⑤ are on page 8

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## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	250	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	340	—	mV/°C	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	38	46	mΩ	$V_{GS} = 10V, I_D = 11A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-12	—	mV/°C	
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 250V, V_{GS} = 0V$
		—	—	200		$V_{DS} = 250V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$
$g_{fs}$	Forward Transconductance	26	—	—	S	$V_{DS} = 25V, I_D = 11A$
$Q_g$	Total Gate Charge	—	73	110	nC	$V_{DD} = 125V, I_D = 11A, V_{GS} = 10V$ ③
$Q_{gd}$	Gate-to-Drain Charge	—	24	—		
$t_{d(on)}$	Turn-On Delay Time	—	18	—	ns	$V_{DD} = 125V, V_{GS} = 10V$ ③ $I_D = 11A$ $R_G = 2.4\Omega$ See Fig. 22
$t_r$	Rise Time	—	17	—		
$t_{d(off)}$	Turn-Off Delay Time	—	32	—		
$t_f$	Fall Time	—	13	—		
$t_{st}$	Shoot Through Blocking Time	100	—	—	ns	$V_{DD} = 200V, V_{GS} = 15V, R_G = 5.1\Omega$
$E_{PULSE}$	Energy per Pulse	—	770	—	μJ	$L = 220nH, C = 0.3\mu F, V_{GS} = 15V$ $V_{DS} = 200V, R_G = 5.1\Omega, T_J = 25^\circ\text{C}$
		—	1380	—		$L = 220nH, C = 0.3\mu F, V_{GS} = 15V$ $V_{DS} = 200V, R_G = 5.1\Omega, T_J = 100^\circ\text{C}$
$C_{iss}$	Input Capacitance	—	4480	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	400	—		$V_{DS} = 25V$
$C_{riss}$	Reverse Transfer Capacitance	—	100	—		$f = 1.0MHz,$
$C_{oss\ eff.}$	Effective Output Capacitance	—	270	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 200V$
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		

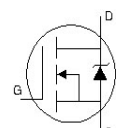


## Avalanche Characteristics

	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	110	mJ
$E_{AR}$	Repetitive Avalanche Energy ①	—	4.6	mJ
$V_{DS(Avalanche)}$	Repetitive Avalanche Voltage ①	300	—	V
$I_{AS}$	Avalanche Current ②	—	11	A

## Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S @ T_C = 25^\circ\text{C}$	Continuous Source Current (Body Diode)	—	—	18	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	72		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 11A, V_{GS} = 0V$ ③
$t_{rr}$	Reverse Recovery Time	—	120	180	ns	$T_J = 25^\circ\text{C}, I_F = 11A, V_{DD} = 50V$
$Q_{rr}$	Reverse Recovery Charge	—	540	810	nC	$di/dt = 100A/\mu s$ ③



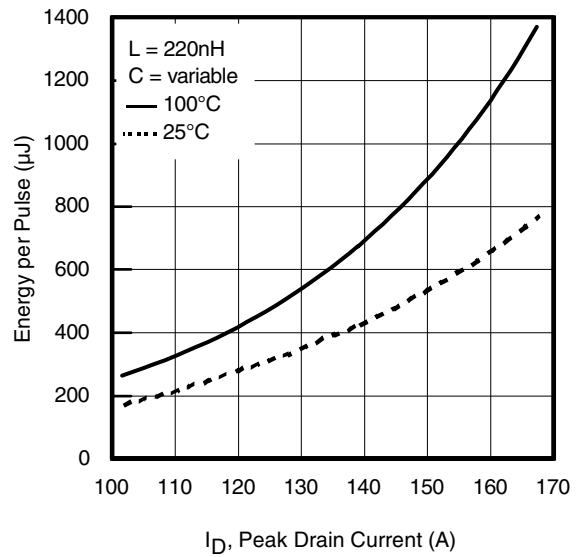
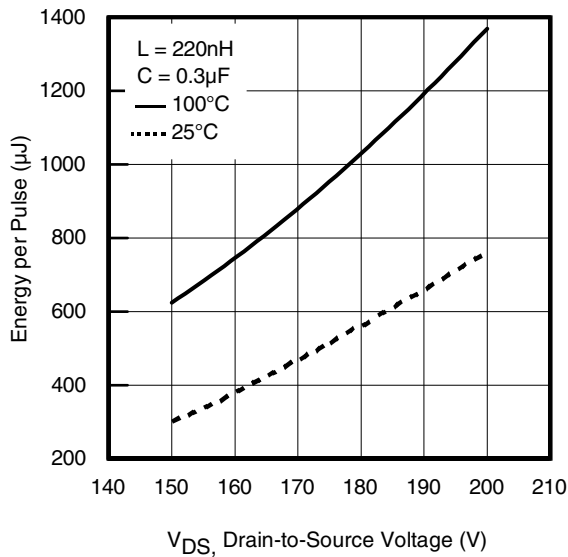
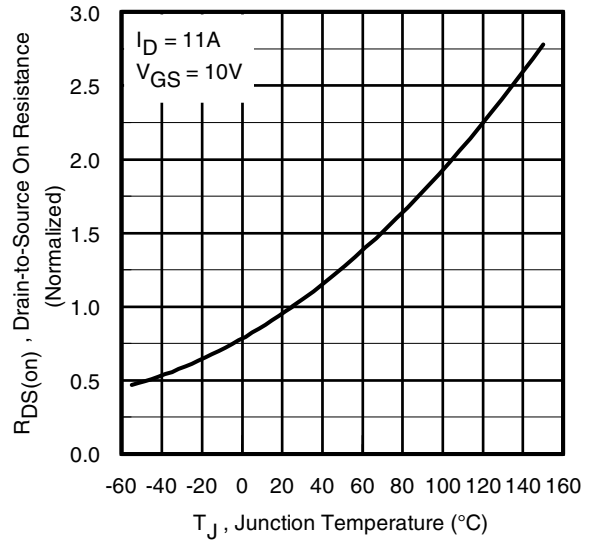
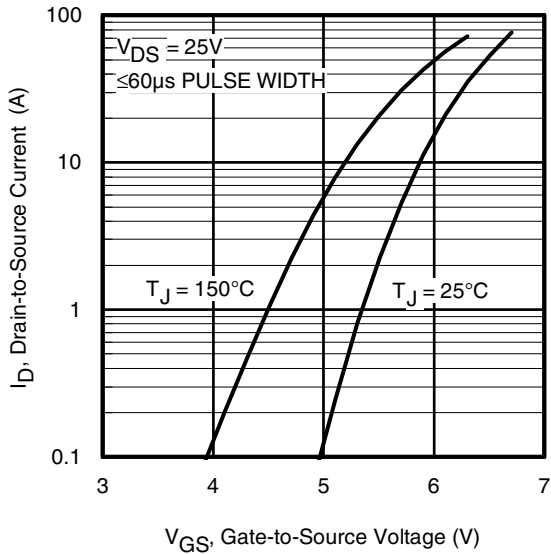
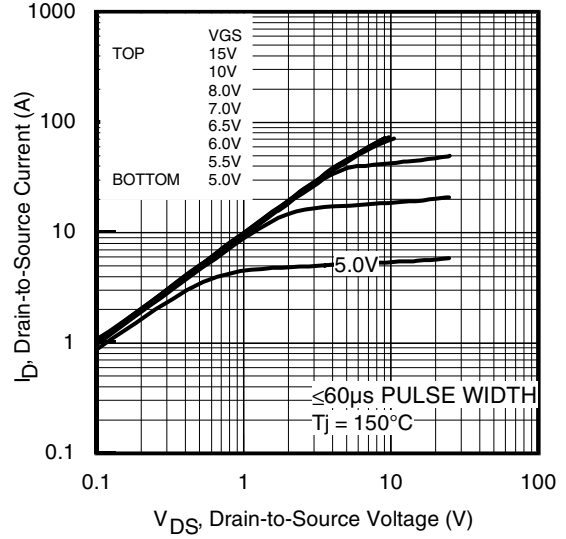
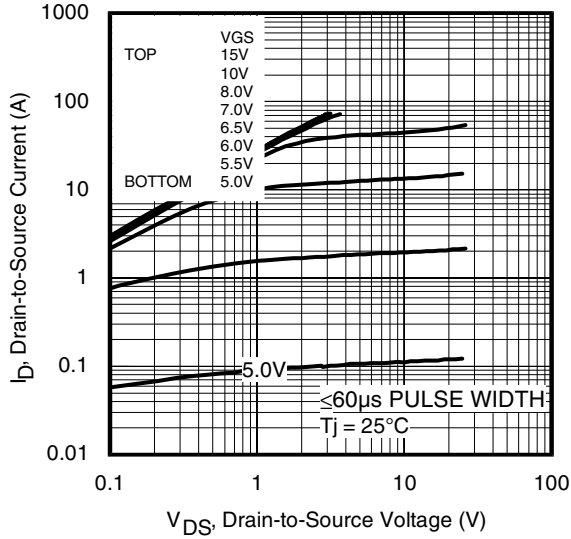
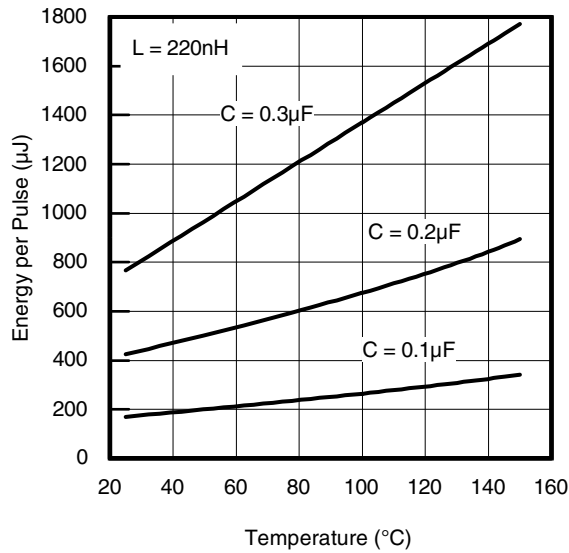
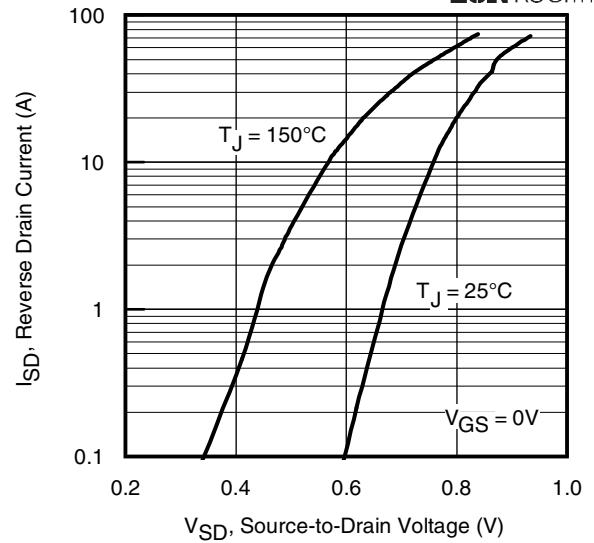


Fig 5. Typical  $E_{PULSE}$  vs. Drain-to-Source Voltage  
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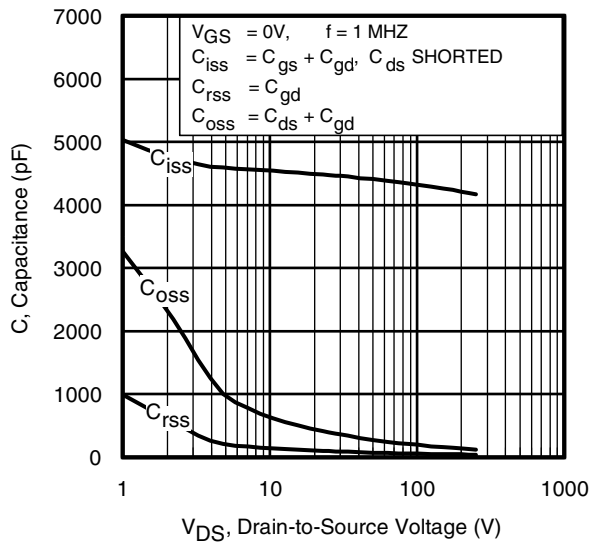
Fig 6. Typical  $E_{PULSE}$  vs. Drain Current



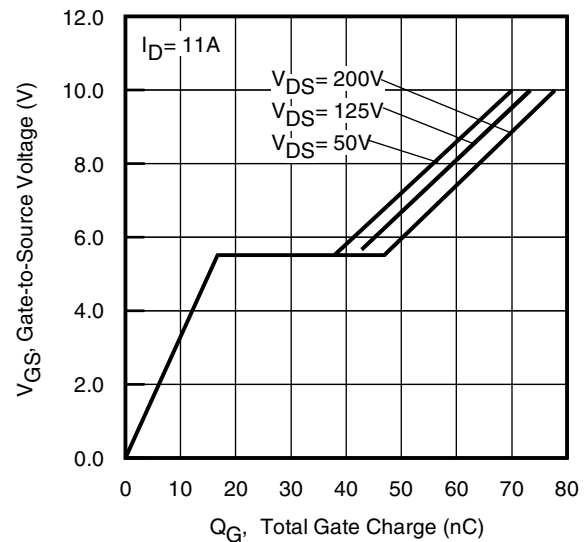
**Fig 7.** Typical  $E_{PULSE}$  vs. Temperature



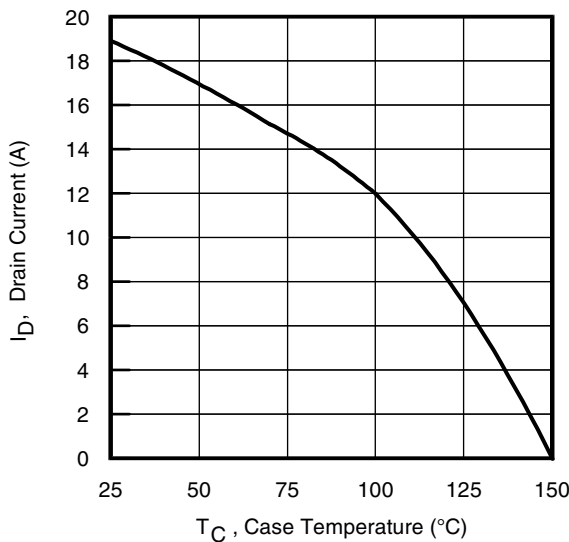
**Fig 8.** Typical Source-Drain Diode Forward Voltage



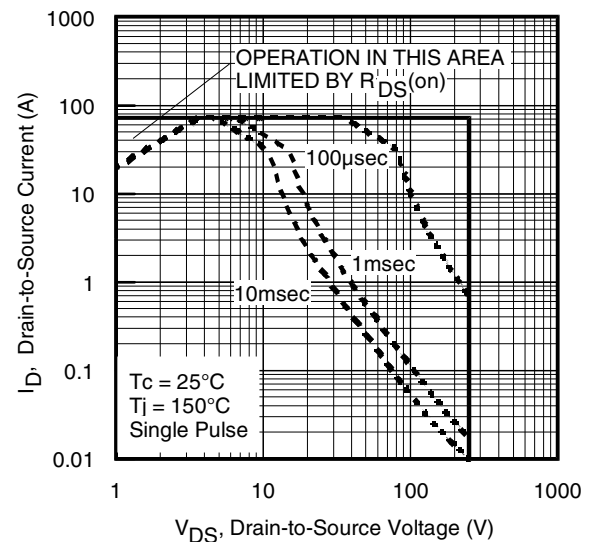
**Fig 9.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 10.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 11.** Maximum Drain Current vs. Case Temperature



**Fig 12.** Maximum Safe Operating Area

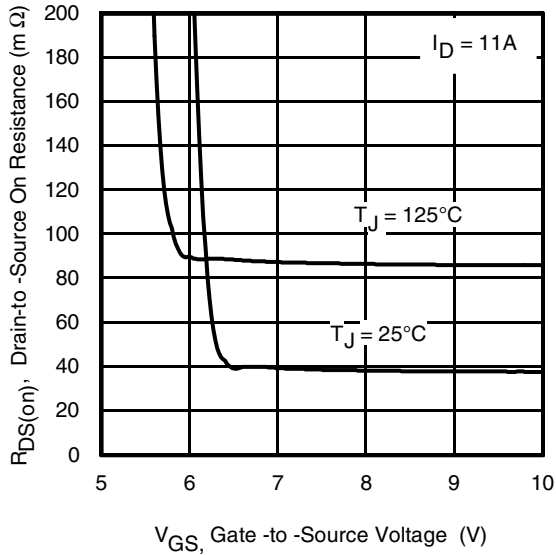


Fig 13. On-Resistance vs. Gate Voltage

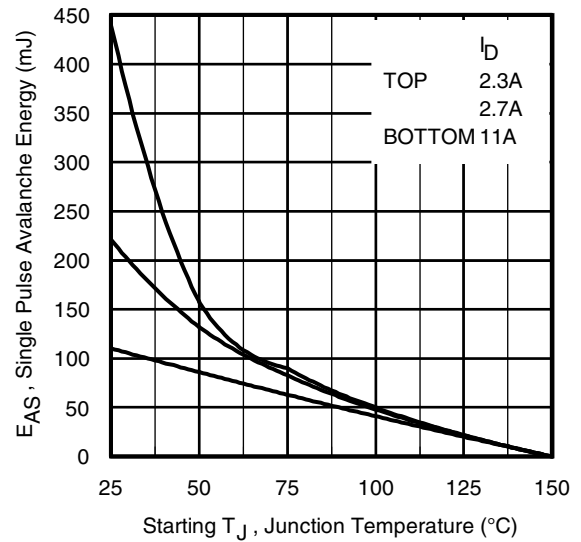


Fig 14. Maximum Avalanche Energy vs. Temperature

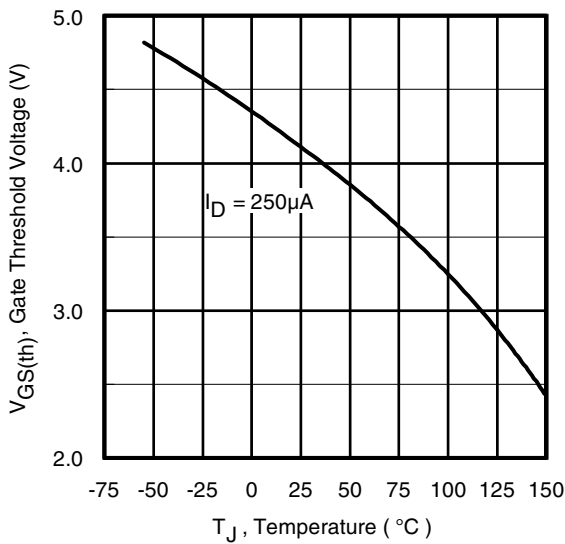


Fig 15. Threshold Voltage vs. Temperature

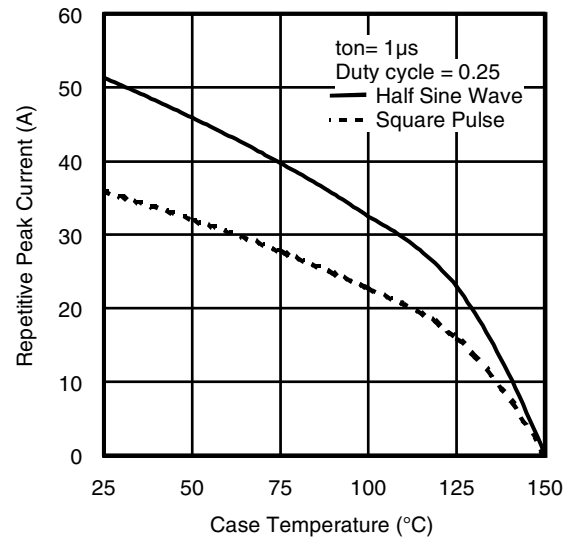


Fig 16. Typical Repetitive peak Current vs. Case temperature

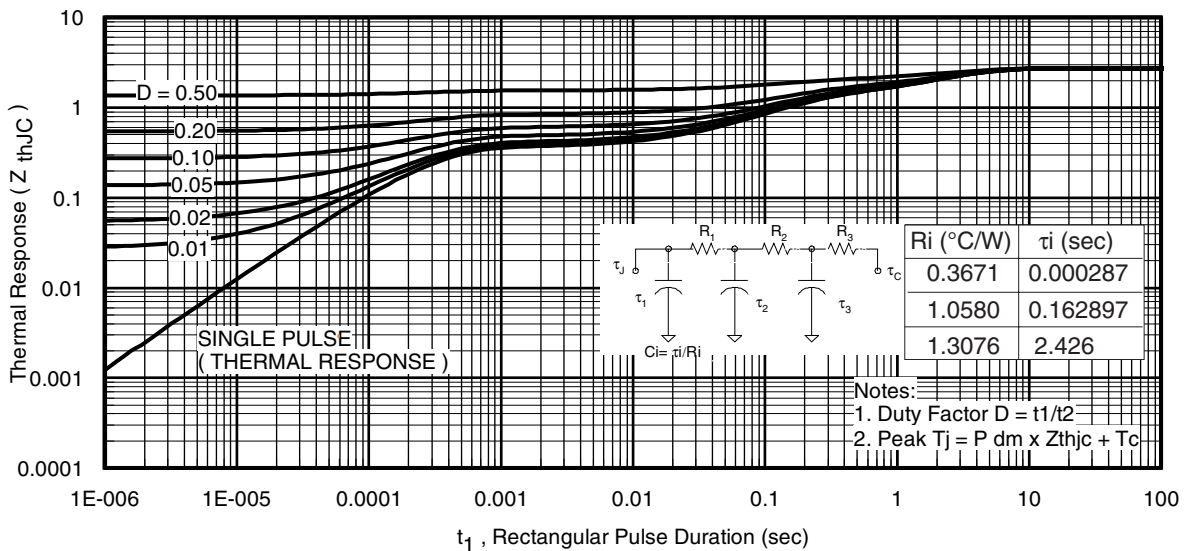
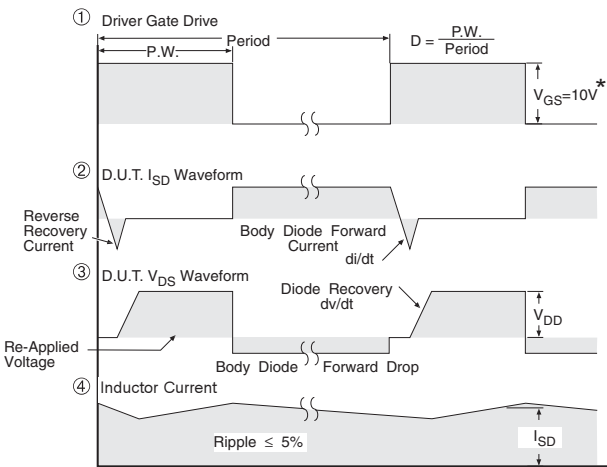
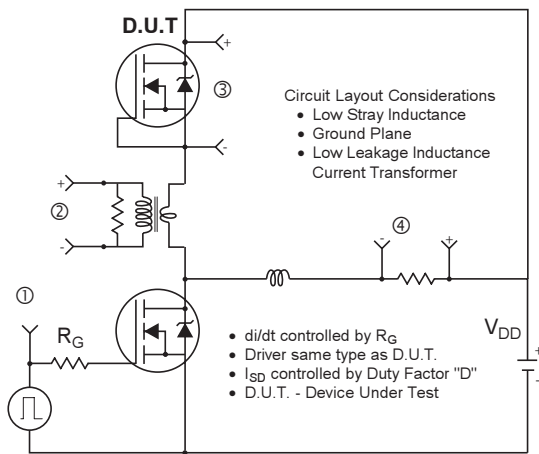
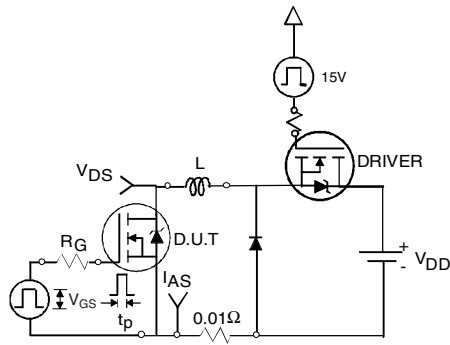


Fig 17. Maximum Effective Transient Thermal Impedance, Junction-to-Case

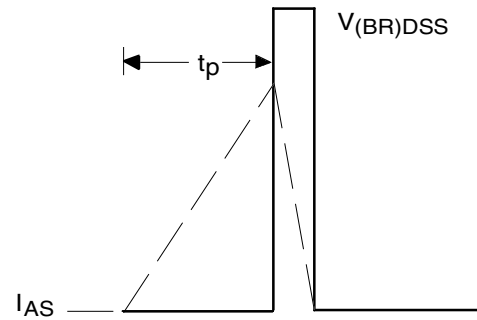


\*  $V_{GS} = 5V$  for Logic Level Devices

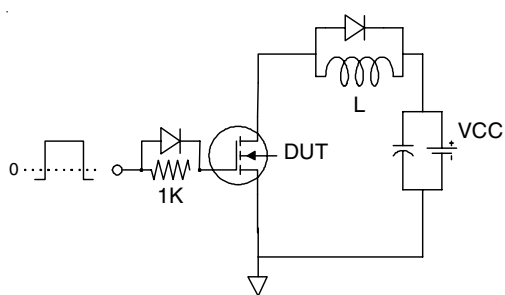
**Fig 18.** Diode Reverse Recovery Test Circuit for N-Channel HEXFET<sup>®</sup> Power MOSFETs



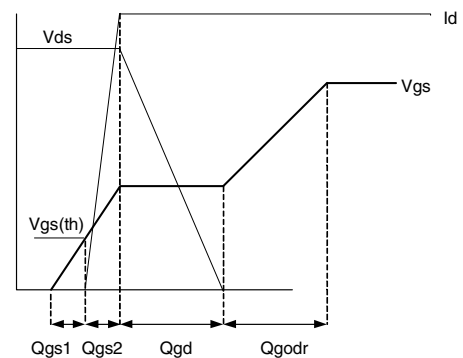
**Fig 19a.** Unclamped Inductive Test Circuit



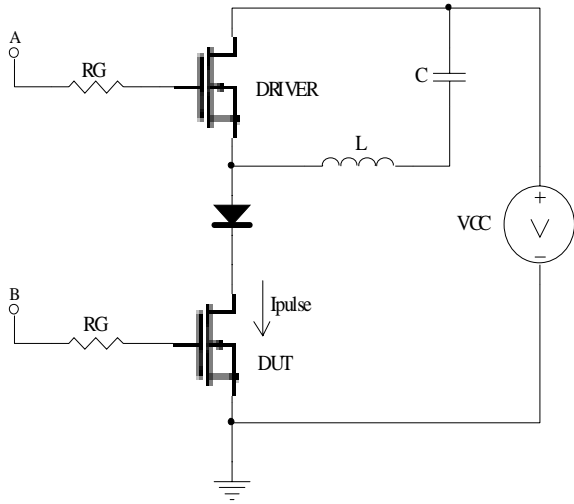
**Fig 19b.** Unclamped Inductive Waveforms



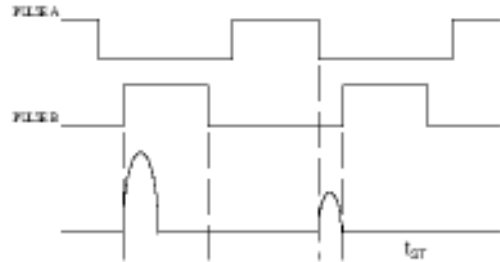
**Fig 20a.** Gate Charge Test Circuit



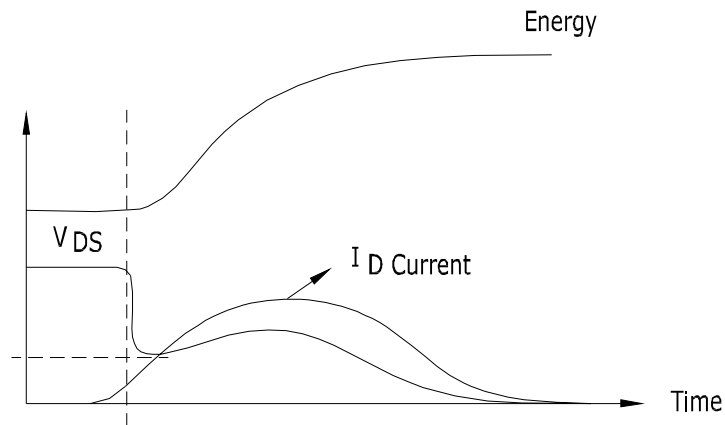
**Fig 20b.** Gate Charge Waveform



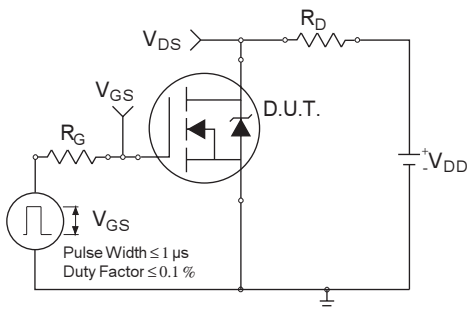
**Fig 21a.**  $t_{st}$  and  $E_{PULSE}$  Test Circuit



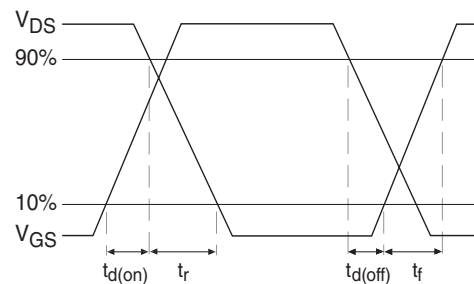
**Fig 21b.**  $t_{st}$  Test Waveforms



**Fig 21c.**  $E_{PULSE}$  Test Waveforms



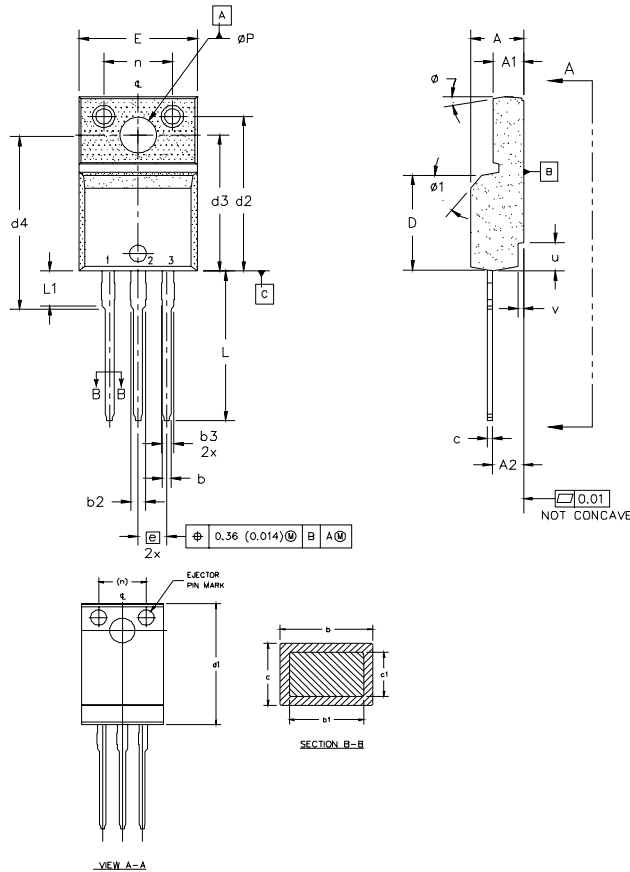
**Fig 22a.** Switching Time Test Circuit



**Fig 22b.** Switching Time Waveforms

# IRFI4229PbF

## TO-220AB Full-Pak Package Outline (Dimensions are shown in millimeters (inches))



NOTES:

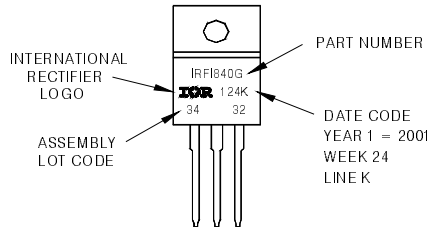
- 1.0 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2.0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- 4.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5.0 DIMENSION b1 APPLY TO BASE METAL ONLY.
- 6.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.
- 7.0 CONTROLLING DIMENSION : INCHES.

SYMBOL	DIMENSIONS				NOTES	LEAD ASSIGNMENTS
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.57	4.83	0.180	0.190		
A1	2.57	2.83	0.101	0.114		
A2	2.51	2.85	0.099	0.112		
b	0.622	0.89	0.024	0.035	5	1.- GATE 2.- DRAIN 3.- SOURCE
b1	0.622	0.838	0.024	0.033		
b2	1.229	1.400	0.048	0.055		
b3	1.229	1.400	0.048	0.055		
c	0.440	0.629	0.017	0.025	4	IGBTs, CoPACK 1.- GATE 2.- COLLECTOR 3.- EMITTER
c1	0.440	0.584	0.017	0.023		
D	8.65	9.80	0.341	0.386		
d1	15.80	16.12	0.622	0.635	3	
d2	13.97	14.22	0.550	0.560		
d3	12.30	12.92	0.484	0.509		
d4	8.64	9.91	0.340	0.390	4	
E	10.36	10.63	0.408	0.419		
e	2.54 BSC		0.100 BSC			
L	13.20	13.73	0.520	0.541	6	
L1	3.10	3.50	0.122	0.138		
n	6.05	6.15	0.238	0.242		
phi P	3.05	3.45	0.120	0.136		
u	2.40	2.50	0.094	0.098		
v	0.40	0.50	0.016	0.020		
phi 1	3"	7"	3"	7"		
phi 1		45°		45°		

## TO-220AB Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WW 24, 2001  
IN THE ASSEMBLY LINE 'K'

Note: 'P' in assembly line position  
indicates 'Lead-Free'



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 1.9\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 11\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ Half sine wave with duty cycle = 0.25,  $t_{on} = 1\mu\text{sec}$ .

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market.  
Qualification Standards can be found on IR's Web site.